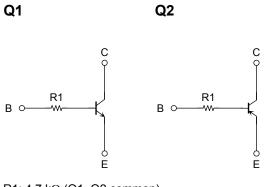
TOSHIBA Transistor Silicon NPN · PNP Epitaxial Type (PCT process) (Bias Resistor built-in Transistor)

RN47A1

Switching, Inverter Circuit, Interface Circuit and Driver Circuit Applications.

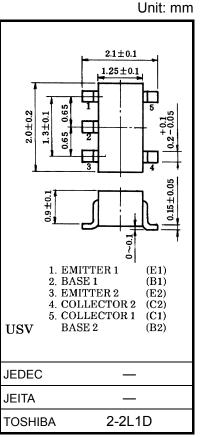
- Two devices are incorporated into an Ultra-Super-Mini (5 pin) package.
- · Incorporating a bias resistor into a transistor reduces parts count.
- Reducing the parts count enables the manufacture of ever more compact equipment and lowers assembly cost.

Equivalent Circuit and Bias Resistor Values



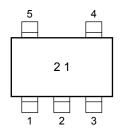
R1: 4.7 kΩ (Q1, Q2 common) Q1: RN1110F

Q2: RN2110F

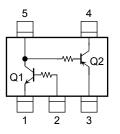


Weight:0.0062g (typ.)

Marking



Equivalent Circuit (top view)



Absolute Maximum Ratings (Ta = 25°C) (Q1)

Characteristics	Symbol	Rating	Unit
Collector-base voltage	V _{CBO}	50	V
Collector-emitter voltage	V _{CEO}	50	V
Emitter-base voltage	V _{EBO}	5	V
Collector current	Ι _C	100	mA

Absolute Maximum Ratings (Ta = 25°C) (Q2)

Characteristics	Symbol	Rating	Unit
Collector-base voltage	V _{CBO}	-50	V
Collector-emitter voltage	V _{CEO}	-50	V
Emitter-base voltage	V _{EBO}	-5	V
Collector current	ΙC	-100	mA

Absolute Maximum Ratings (Ta = 25°C) (Q1, Q2 common)

Characteristics	Symbol	Rating	Unit
Collector power dissipation	P _C (Note 1)	200	mW
Junction temperature	Tj	150	°C
Storage temperature range	T _{stg}	-55~150	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: Total rating

Electrical Characteristics (Ta = 25°C) (Q1)

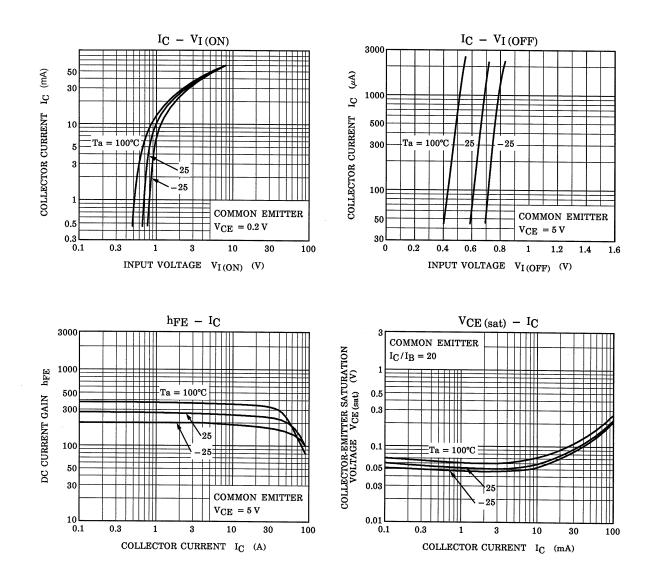
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current	I _{CBO}	$V_{CB} = 50 \text{ V}, \text{ I}_{E} = 0$	_	_	100	nA
Emitter cut-off current	I _{EBO}	$V_{EB}=5~V,~I_C=0$	_	_	100	nA
DC current gain	h _{FE}	$V_{CE} = 5 \text{ V}, \text{ I}_{C} = 1 \text{ mA}$	120	_	700	
Collector-emitter saturation voltage	V _{CE (sat)}	$I_{C} = 5 \text{ mA}, I_{B} = 0.25 \text{ mA}$	_	0.1	0.3	V
Transition frequency	f _T	$V_{CE} = 10 \text{ V}, I_{C} = 5 \text{ mA}$	_	250	_	MHz
Collector output capacitance	C _{ob}	$V_{CB} = 10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$	_	3	_	pF
Input resistor	R1	—	3.29	4.7	6.11	kΩ

Electrical Characteristics (Ta = 25°C) (Q2)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current	I _{CBO}	$V_{CB}=-50~V,~I_{E}=0$	_	_	-100	nA
Emitter cut-off current	I _{EBO}	$V_{EB}=-5~V,~I_C=0$	_	_	-100	nA
DC current gain	h _{FE}	$V_{CE} = -5 \text{ V}, \text{ I}_{C} = -1 \text{ mA}$	120	_	400	
Collector-emitter saturation voltage	V _{CE (sat)}	$I_C = -5 \text{ mA}, I_B = -0.25 \text{ mA}$	_	-0.1	-0.3	V
Transition frequency	f _T	$V_{CE} = -10 \text{ V}, \text{ I}_{C} = -5 \text{ mA}$	_	200	_	MHz
Collector output capacitance	C _{ob}	$V_{CB} = -10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$	_	3		pF
Input resistor	R1	—	3.29	4.7	6.11	kΩ

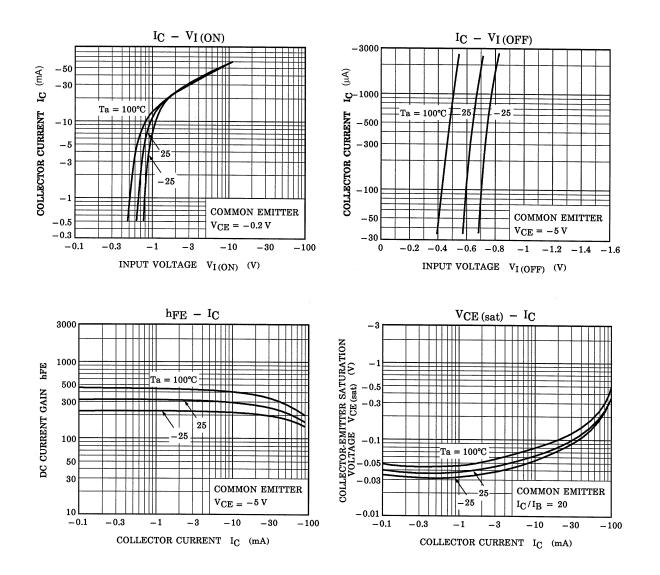
TOSHIBA

Q1



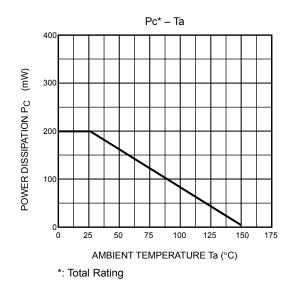
TOSHIBA

Q2



TOSHIBA

Q1, Q2 Common



RESTRICTIONS ON PRODUCT USE

20070701-EN GENERAL

- The information contained herein is subject to change without notice.
- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor
 devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical
 stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety
 in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such
 TOSHIBA products could cause loss of human life, bodily injury or damage to property.

In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.

- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.).These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in his document shall be made at the customer's own risk.
- The products described in this document shall not be used or embedded to any downstream products of which manufacture, use and/or sale are prohibited under any applicable laws and regulations.
- The information contained herein is presented only as a guide for the applications of our products. No responsibility
 is assumed by TOSHIBA for any infringements of patents or other rights of the third parties which may result from
 its use. No license is granted by implication or otherwise under any patents or other rights of TOSHIBA or the third
 parties.
- Please contact your sales representative for product-by-product details in this document regarding RoHS compatibility. Please use these products in this document in compliance with all applicable laws and regulations that regulate the inclusion or use of controlled substances. Toshiba assumes no liability for damage or losses occurring as a result of noncompliance with applicable laws and regulations.